Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
09/683,448	TOYAMA, KENTARO	
Examiner	Art Unit	
Ashutosh Upreti	2623	

SEARCHED					
Class	Subclass	Date	Examiner		
382	1037	02/15/05	A·U.		
348	14.01	02/16/05	A·u.		
348	14.16	02/16/05	A.U.		
382	ALL	02/16/05	A.u.		

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
382	103,118	02/15/05	A·u.			
348	14.01,14.08,	02/16/05	A.U.			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted Jon Chang 382/103,118 + To see search notes history	02/14/05	A∙u.		
Inventorship Search	02/14/05	A·U,		
Consulted Jon Chang All of 382	02/16/05	A·U.		
IEEE (face or facial) and pose (face or facial) and pose and head	02/17/05	A.U.		
Jon searched in 382 \$ 348 see search history	02/17/05	A.U.		